# Abstracts

## In-Circuit Electro-Optic Field Mapping for Function Test and Characterization of MMICs

*G. David, R. Tempel, I. Wolff and D. Jager. "In-Circuit Electro-Optic Field Mapping for Function Test and Characterization of MMICs." 1996 MTT-S International Microwave Symposium Digest 96.3 (1996 Vol. III [MWSYM]): 1533-1536.*

In this paper, the results of 2D electro-optic mapping of electric field distributions in two coplanar MMICs are presented. It is demonstrated that the obtained images of the field distributions can be used for function test, failure localization and for a quantitative high frequency characterization of the circuits.

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